


<b>Search Notes</b> 	<b>Application/Control No.</b> 10708738	<b>Applicant(s)/Patent Under Reexamination</b> LEE, YEUN-JONQ
	<b>Examiner</b> Shih, Haoshian	<b>Art Unit</b> 2173

SEARCHED			
Class	Subclass	Date	Examiner
707	3	5/17/2007	HSS
715		5/17/2007	HSS

SEARCH NOTES		
Search Notes	Date	Examiner
Searched EAST	5/17/2007	HSS

INTERFERENCE SEARCH			
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